2SD1276, 2SD1276A

Silicon NPN triple diffusion planar type darlington

For power amplification

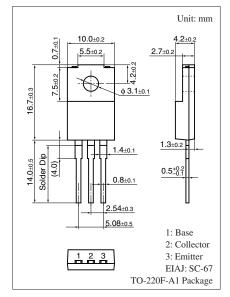
Complementary to 2SB0950 and 2SB0950A

Features

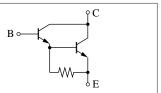
- \bullet High forward current transfer ratio h_{FE}
- High-speed switching
- Full-pack package which can be installed to the heat sink with one screw

Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SD1276	V _{CBO}	60	V
(Emitter open)	2SD1276A		80	
Collector-emitter voltage	2SD1276	V _{CEO}	60	V
(Base open)	2SD1276A		80	
Emitter-base voltage (Col	V _{EBO}	5	V	
Collector current	I _C	4	А	
Peak collector current	I _{CP}	8	А	
Collector power	$T_C = 25^{\circ}C$	P _C	40	W
dissipation		2.0		
Junction temperature	Tj	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	



Internal Connection



Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SD1276	V _{CEO}	$I_{\rm C} = 30 \text{ mA}, I_{\rm B} = 0$	60			V
(Base open)	2SD1276A			80			
Base-emitter voltage		V _{BE}	$V_{CE} = 3 V, I_C = 3 A$			2.5	V
Collector-base cutoff	2SD1276	I _{CBO}	$V_{CB} = 60 V, I_E = 0$			200	μΑ
current (Emitter open)	2SD1276A		$V_{CB} = 80 V, I_E = 0$			200	
Collector-emitter cutoff	2SD1276	I _{CEO}	$V_{CE} = 30 \text{ V}, I_B = 0$			500	μΑ
current (Base open)	2SD1276A		$V_{CE} = 40 \text{ V}, I_B = 0$			500	
Emitter-base cutoff current (Collector open)		I _{EBO}	$V_{EB} = 5 V, I_C = 0$			2	mA
Forward current transfer ratio		h _{FE1}	$V_{CE} = 3 V, I_C = 0.5 A$	1 0 0 0			
		h _{FE2} *	$V_{CE} = 3 V, I_C = 3 A$	1 0 0 0		10000	
Collector-emitter saturation voltage		V _{CE(sat)1}	$I_{C} = 3 \text{ A}, I_{B} = 12 \text{ mA}$			2.0	V
		V _{CE(sat)2}	$I_{C} = 5 \text{ A}, I_{B} = 20 \text{ mA}$			4.0	
Transition frequency		f _T	$V_{CE} = 10 \text{ V}, I_C = 0.5 \text{ A}, f = 1 \text{ MHz}$		20		MHz
Turn-on time		t _{on}	$I_{C} = 3 \text{ A}, I_{B1} = 12 \text{ mA}, I_{B2} = -12 \text{ mA},$		0.5		μs
Storage time		t _{stg}	$V_{CC} = 50 V$		4.0		μs
Fall time		t _f			1.0		μs

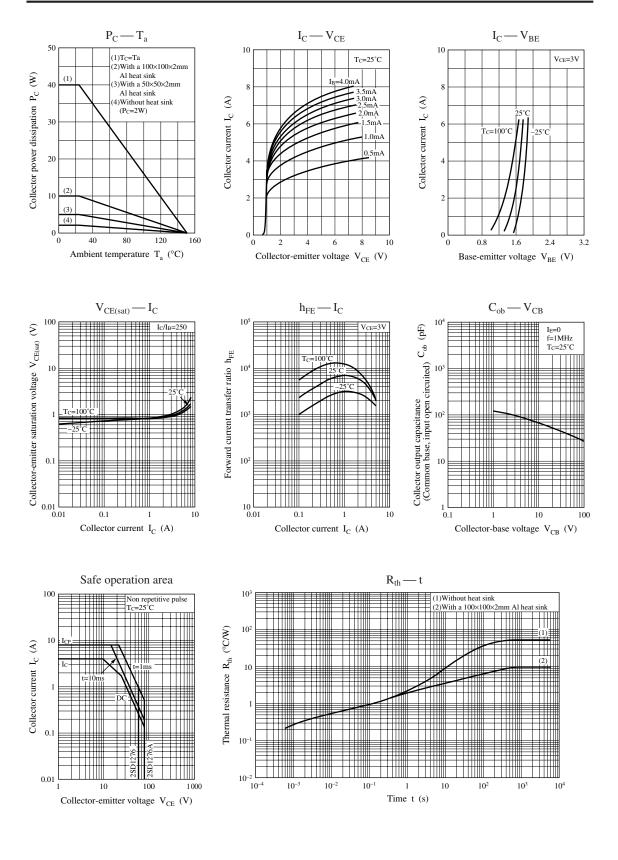
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

Rank	R	Q	Р
h _{FE2}	1000 to 2500	2000 to 5000	4000 to 10000

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2SD1276, 2SD1276A

Panasonic



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